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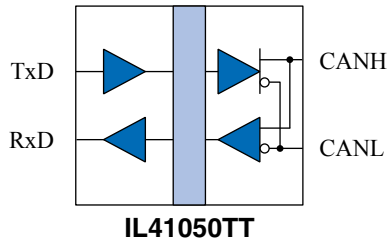
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## Basic Function Isolated CAN Transceiver

### Functional Diagram



V <sub>DD2</sub> (V)	TxD <sup>(1)</sup>	S	CANH	CANL	Bus State	RxD
4.75 to 5.25	↓	Low <sup>(2)</sup>	High	Low	Dominant	Low
4.75 to 5.25	X	High	V <sub>DD2</sub> /2	V <sub>DD2</sub> /2	Recessive	High
4.75 to 5.25	↑	X	V <sub>DD2</sub> /2	V <sub>DD2</sub> /2	Recessive	High
<2V (no pwr)	X	X	0<V<2.5	0<V<2.5	Recessive	High
2<V <sub>DD2</sub> <4.75	>2V	X	0<V<2.5	0<V<2.5	Recessive	High

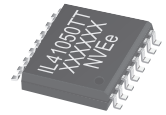
**Table 1.** Function table.

#### Notes:

1. TxD input is edge triggered: ↑ = Logic Lo to Hi, ↓ = Hi to Lo
  2. Valid for logic state as described or open circuit
- X = don't care

### Features

- Industry-standard pinout
- 5000 V<sub>RMS</sub> isolation (“V”-Version)
- 180 ns typical loop delay
- 70 mA maximum bus-side dynamic supply current
- 12 mA maximum quiescent recessive supply current
- 1 Mbps
- Fully compliant with the ISO 11898-2 CAN standard
- -55°C to +100°C operating temperature
- 3 V to 5.5 V power supplies
- >110-node fan-out
- 600 V<sub>RMS</sub> working voltage per VDE V 0884-10
- 44000 year barrier life
- ±500 V CDM ESD
- 50 kV/μs typ.; 30 kV/μs min. common mode transient immunity
- No carrier or clock for low emissions and EMI susceptibility
- Transmit data (TxD) dominant time-out function
- Edge triggered, non-volatile input improves noise performance
- Thermal shutdown protection
- Bus power short-circuit protection
- No “S” or Vref functions
- 0.3" True 8™ mm 16-pin packages
- UL 1577 recognized; VDE V 0884-1- certified



### Applications

- Factory automation
- Battery management systems
- Noise-critical CAN
- DeviceNet

### Description

The IL41050TT is a galvanically isolated, CAN (Controller Area Network) transceiver containing basic functions but without “S” or Vref pins. It is a direct replacement for the Texas Instruments ISO1050DW with much better reliability and longer barrier life, less EMI emissions, and true 8 mm external creepage.

The IL41050 family provides isolated differential transmit capability to the bus and isolated differential receive capability to the CAN controller via NVE’s patented\* IsoLoop spintronic Giant Magnetoresistance (GMR) technology.

A unique ceramic/polymer composite barrier provides excellent isolation and virtually unlimited barrier life.

Designed for harsh CAN and DeviceNet environments, IL41050 transceivers have transmit data dominant time-out, bus pin transient protection, a rugged Charged Device Model ESD rating, thermal shutdown protection, and short-circuit protection. Unique edge-triggered inputs improve noise performance.

## Absolute Maximum Ratings<sup>(1)(2)</sup>

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Storage temperature	$T_S$	-55		150	°C	
Junction temperature	$T_J$	-55		150	°C	
Ambient operating temperature	$T_A$	-55		100	°C	
DC voltage at CANH and CANL pins	$V_{CANH}, V_{CANL}$	-45		45	V	$0 V < V_{DD2} < 5.25 V$ ; indefinite duration
Supply voltage	$V_{DD1}, V_{DD2}$	-0.3		7	V	
Digital input voltage	$V_{TXD}, V_S$	-0.3		$V_{DD} + 0.3$	V	
Digital output voltage	$V_{RXD}$	-0.3		$V_{DD} + 0.3$	V	
DC voltage at $V_{REF}$	$V_{REF}$	-0.3		$V_{DD} + 0.3$	V	
Transient voltage at CANH or CANL	$V_{tr(CAN)}$	-150		150	V	
Electrostatic discharge at all pins	$V_{esd}$	-4000		4000	V	Human body model
Electrostatic discharge at all pins	$V_{esd}$	-500		500	V	Machine model

## Recommended Operating Conditions

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Supply voltage	$V_{DD1}$ $V_{DD2}$	3.0 4.75		5.5 5.25	V	
Junction temperature	$T_J$	-55		140	°C	
Input voltage at any bus terminal (separately or common mode)	$V_{CANH}$ $V_{CANL}$	-12		12	V	
High-level digital input voltage <sup>(3)(4)</sup>	$V_{IH}$	2.0 2.4 2.0		$V_{DD1}$ $V_{DD1}$ $V_{DD2}$	V	$V_{DD1} = 3.3 V$ $V_{DD1} = 5.0 V$ $V_{DD2} = 5.0 V$
Low-level digital input voltage <sup>(3)(4)</sup>	$V_{IL}$	0		0.8	V	
Digital output current (Rx/D)	$I_{OH}$	-8		8	mA	$V_{DD1} = 3.3V \text{ to } 5V$
Ambient operating temperature	$T_A$	-55		100	°C	
Digital input signal rise and fall times	$t_{IR}, t_{IF}$			1	µs	

## Insulation Specifications

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Creepage distance (external)		8.03	8.3		mm	Per IEC 60601
Total barrier thickness (internal)		0.012	0.013		mm	
Barrier resistance	$R_{IO}$		$>10^{14}$		Ω	500 V
Barrier capacitance	$C_{IO}$		7		pF	f = 1 MHz
Leakage current			0.2		µA <sub>RMS</sub>	240 V <sub>RMS</sub> , 60 Hz
Comparative Tracking Index	CTI	≥175			V	Per IEC 60112
High voltage endurance (maximum barrier voltage for indefinite life)	AC	1000			$V_{RMS}$	At maximum operating temperature
	DC	1500			$V_{DC}$	
Barrier life			44000		Years	100°C, 1000 V <sub>RMS</sub> , 60% CL activation energy

## Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Junction–Ambient Thermal Resistance	$\theta_{JA}$	QSOP	60		°C/W	Soldered to double- sided board; free air
		0.15" SOIC	60			
		0.3" SOIC	60			
Junction–Case (Top) Thermal Resistance	$\Psi_{JT}$	QSOP	10		°C/W	
		0.15" SOIC	10			
		0.3" SOIC	20			
Power Dissipation	$P_D$			675 700 800	mW	

## Safety and Approvals

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**VDE V 0884-10** (File Number 5016933-4880-0001)

2.5 kV-rated version (IL41050TTE)

- Working Voltage ( $V_{IORM}$ )  $600 V_{RMS}$  ( $848 V_{PK}$ ); basic insulation; pollution degree 2
- Isolation voltage ( $V_{ISO}$ )  $2500 V_{RMS}$
- Surge rating 4 kV

5 kV-rated version (IL41050TTVE)

- Working Voltage ( $V_{IORM}$ )  $600 V_{RMS}$  ( $848 V_{PK}$ ); basic insulation; pollution degree 2
- Isolation voltage ( $V_{ISO}$ )  $5000 V_{RMS}$
- Surge rating 4 kV

Safety-Limiting Values	Symbol	Value	Units
Safety rating ambient temperature	$T_S$	180	$^{\circ}C$
Safety rating power (180 $^{\circ}C$ )	$P_S$	270	mW
Supply current safety rating (total of supplies)	$I_S$	54	mA

**IEC 61010-1** (Edition 2; TUV Certificate Numbers N1502812; N1502812-101)

Reinforced Insulation; Pollution Degree II; Material Group III

Working Voltage  $600 V_{RMS}$

**UL 1577** (Component Recognition Program File Number E207481)

2.5 kV-rated version (IL41050TTE)

Each part tested at  $3 kV_{RMS}$  ( $4.24 kV_{PK}$ ) for 1 second; each lot sample tested at  $2.5 kV_{RMS}$  ( $3.54 kV_{PK}$ ) for 1 minute

5 kV-rated version (IL41050TTVE)

Each part tested at  $6 kV_{RMS}$  ( $8.48 kV_{PK}$ ) for 1 second; each lot sample tested at  $5 kV_{RMS}$  ( $7.07 kV_{PK}$ ) for 1 minute

## Soldering Profile

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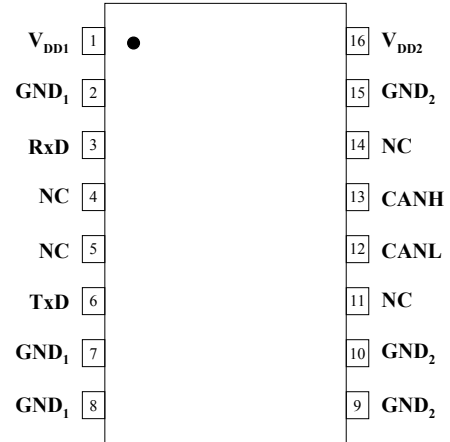
Per JEDEC J-STD-020C; MSL=1

## Notes:

1. Absolute Maximum specifications mean the device will not be damaged if operated under these conditions. It does not guarantee performance.
2. All voltages are with respect to network ground except differential I/O bus voltages.
3. The TxD input is edge sensitive. Voltage magnitude of the input signal is specified, but edge rate specifications must also be met.
4. The maximum time allowed for a logic transition at the TxD input is 1  $\mu s$ .

## IL41050TT Pin Connections

1	V <sub>DD1</sub>	V <sub>DD1</sub> power supply input
2	GND <sub>1</sub>	V <sub>DD1</sub> power supply ground return (pin 2 is internally connected to pin 8)
3	RxD	Receive Data output
4	NC	No internal connection
5	NC	No internal connection
6	TxD	Transmit Data input
7,8	GND <sub>1</sub>	V <sub>DD1</sub> power supply ground return (pin 8 is internally connected to pin 2)
9,10	GND <sub>2</sub>	V <sub>DD2</sub> power supply ground return (pin 9 is internally connected to pin 15)
11	NC	No internal connection
12	CANL	Low level CANbus line
13	CANH	High level CANbus line
14	NC	No internal connection
15	GND <sub>2</sub>	V <sub>DD2</sub> power supply ground return (pin 15 is internally connected to pin 9)
16	V <sub>DD2</sub>	V <sub>DD2</sub> isolation power supply input



## Operating Specifications

Electrical Specifications ( $T_{min}$ to $T_{max}$ and $V_{DD1}$ , $V_{DD2}$ = 4.75 V to 5.25 V unless otherwise stated)						
Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
<b>Power Supply Current</b>						
Quiescent supply current (recessive)	$I_{QVDD1}$	1 0.7	1.75 1.4	3.0 2.0	mA	$dr = 0$ bps; $V_{DD1} = 5$ V $dr = 0$ bps; $V_{DD1} = 3.3$ V
Dynamic supply current (dominant)	$I_{VDD1}$	1.2 0.9	2.0 1.6	3.2 2.2	mA	$dr = 1$ Mbps, $R_L = 60\Omega$ ; $V_{DD1} = 5$ V $dr = 1$ Mbps, $R_L = 60\Omega$ ; $V_{DD1} = 3.3$ V
Quiescent supply current (recessive)	$I_{QVDD2}$	3.5	7	12	mA	0 bps
Dynamic supply current (dominant)	$I_{VDD2}$	26	52	70	mA	1 Mbps, $R_L = 60\Omega$
<b>Transmitter Data input (TxD)<sup>(1)</sup></b>						
High level input voltage $\uparrow$	$V_{IH}$	2.4		5.25	V	$V_{DD1} = 5$ V; recessive
High level input voltage $\uparrow$	$V_{IH}$	2.0		3.6	V	$V_{DD1} = 3.3$ V; recessive
Low level input voltage $\downarrow$	$V_{IL}$	-0.3		0.8	V	Output dominant
TxD input rise and fall time <sup>(2)</sup>	$t_r$			1	$\mu$ s	10% to 90% 
High level input current	$I_{IH}$	-10		10	$\mu$ A	$V_{TxD} = V_{DD1}$
Low level input current	$I_{IL}$	10		10	$\mu$ A	$V_{TxD} = 0$ V
<b>Receiver Data output (RxD)</b>						
High level output current	$I_{OH}$	-2	-8.5	-20	mA	$V_{RxD} = 0.8 V_{DD1}$
Low level output current	$I_{OL}$	2	8.5	20	mA	$V_{RxD} = 0.45$ V
Fail-safe supply voltage <sup>(4)</sup>	$V_{DD2}$	3.6		3.9	V	
<b>Bus lines (CANH and CANL)</b>						
Recessive voltage at CANH pin	$V_{O(reces)}$ CANH	2.0	2.5	3.0	V	$V_{TxD} = V_{DD1}$ , no load
Recessive voltage at CANL pin	$V_{O(reces)}$ CANL	2.0	2.5	3.0	V	$V_{TxD} = V_{DD1}$ , no load
Recessive current at CANH pin	$I_{O(reces)}$ CANH	-2.5		+2.5	mA	$-27V < V_{CANH} < +32V$ ; $0V < V_{DD2} < 5.25V$
Recessive current at CANL pin	$I_{O(reces)}$ CANL	-2.5		+2.5	mA	$-27V < V_{CANL} < +32V$ ; $0V < V_{DD2} < 5.25V$
Dominant voltage at CANH pin	$V_{O(dom)}$ CANH	3.0	3.6	4.25	V	$V_{TxD} = 0$ V
Dominant voltage at CANL pin	$V_{O(dom)}$ CANL	0.5	1.4	1.75	V	$V_{TxD} = 0$ V
Differential bus input voltage ( $V_{CANH} - V_{CANL}$ )	$V_{i(dif)(bus)}$	1.5	2.25	3.0	V	$V_{TxD} = 0$ V; dominant $42.5 \Omega < R_L < 60 \Omega$
		-120	0	+50	mV	$V_{TxD} = V_{DD1}$ ; recessive; no load
Short-circuit output current at CANH	$I_{O(sc)}$ CANH	-45	-70	-95	mA	$V_{CANH} = 0$ V, $V_{TxD} = 0$
Short-circuit output current at CANL	$I_{O(sc)}$ CANL	45	70	120	mA	$V_{CANL} = 36$ V, $V_{TxD} = 0$
Differential receiver threshold voltage	$V_{i(dif)(th)}$	0.5	0.7	0.9	V	$-5V < V_{CANL} < +10V$ ; $-5V < V_{CANH} < +10V$
Differential receiver input voltage hysteresis	$V_{i(dif)(hys)}$	50	70	100	mV	$-5V < V_{CANL} < +10V$ ; $-5V < V_{CANH} < +10V$
Common Mode input resistance at CANH	$R_{i(CM)(CANH)}$	15	25	37	k $\Omega$	
Common Mode input resistance at CANL	$R_{i(CM)(CANL)}$	15	25	37	k $\Omega$	
Matching between Common Mode input resistance at CANH, CANL	$R_{i(CM)(m)}$	-3	0	+3	%	$V_{CANL} = V_{CANH}$
Differential input resistance	$R_{i(dif)}$	25	50	75	k $\Omega$	
Input capacitance, CANH	$C_{i(CANH)}$		7.5	20	pF	$V_{TxD} = V_{DD1}$
Input capacitance, CANL	$C_{i(CANL)}$		7.5	20	pF	$V_{TxD} = V_{DD1}$
Differential input capacitance	$C_{i(dif)}$		3.75	10	pF	$V_{TxD} = V_{DD1}$
Input leakage current at CANH	$I_{LI(CANH)}$	100	170	250	$\mu$ A	$V_{CANH} = 5$ V, $V_{DD2} = 0$
Input leakage current at CANL	$I_{LI(CANL)}$	100	170	250	$\mu$ A	$V_{CANL} = 5$ V, $V_{DD2} = 0$
<b>Thermal Shutdown</b>						
Shutdown junction temperature	$T_{i(SD)}$	155	165	180	$^{\circ}$ C	

**Timing Characteristics** (60 Ω / 100 pF bus loading; 20 pF Rx/D load; see Fig. 1)

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
TxD to bus active delay	$t_{d(TxD-BUSon)}$	44 36	93 96	160 128	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
TxD to bus inactive delay	$t_{d(TxD-BUSoff)}$	34 37	68 71	110 113	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Bus active to Rx/D delay	$t_{d(BUSon-RxD)}$	29 32	63 66	125 128	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Bus inactive to Rx/D delay	$t_{d(BUSoff-RxD)}$	69 72	108 111	170 173	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Loop delay low-to-high or high-to-low	$T_{LOOP}$	74	180	210	ns	$V_S = 0\text{ V}$ ; "Typ." at 25°C and nominal loads
TxD dominant time for timeout	$T_{dom(TxD)}$	250	457	765	μs	$V_{TxD} = 0\text{ V}$ $3.0\text{ V} > V_{DD1} < 5.5\text{ V}$
Common Mode Transient Immunity (TxD Logic High or Logic Low)	$ CM_H ,  CM_L $	30	50		kV/μs	$R_L = 60\ \Omega$ ; $V_{CM} = 1500\text{ V}_{DC}$ ; $t_{TRANSIENT} = 25\text{ ns}$

**Magnetic Field Immunity<sup>(3)</sup>** ( $V_{DD2} = 5\text{ V}, 3\text{ V} < V_{DD1} < 5.5\text{ V}$ )

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Power Frequency Magnetic Immunity	$H_{PF}$	4000	6000		A/m	50Hz/60Hz
Pulse Magnetic Field Immunity	$H_{PM}$	6000	7000		A/m	$t_p = 8\ \mu\text{s}$
Damped Oscillatory Magnetic Field	$H_{OSC}$	6000	7000		A/m	0.1Hz – 1MHz
Cross-axis Immunity Multiplier	$K_X$		2			See Fig. 4

**Notes:**

1. The TxD input is edge sensitive. Voltage magnitude of the input signal is specified, but edge rate specifications must also be met.
2. The maximum time allowed for a logic transition at the TxD input is 1 μs.
3. Test and measurement methods are given in the Electromagnetic Compatibility section on p. 10.
4. If  $V_{DD2}$  falls below the specified failsafe supply voltage, Rx/D will go High.

## Timing Test Circuit

Timing parameters are measured with  $60\ \Omega / 100\ \text{pF}$  bus line loading and  $20\ \text{pF}$  on RxD as shown in Figure 1 below:

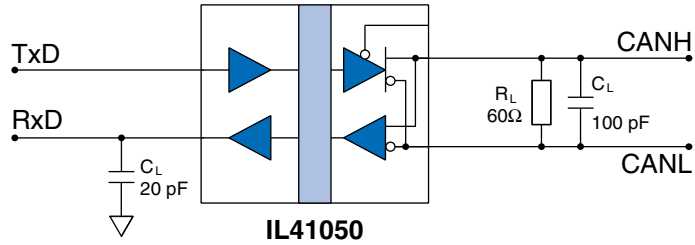


Figure 1. Timing characteristics test circuit.

## Block Diagram

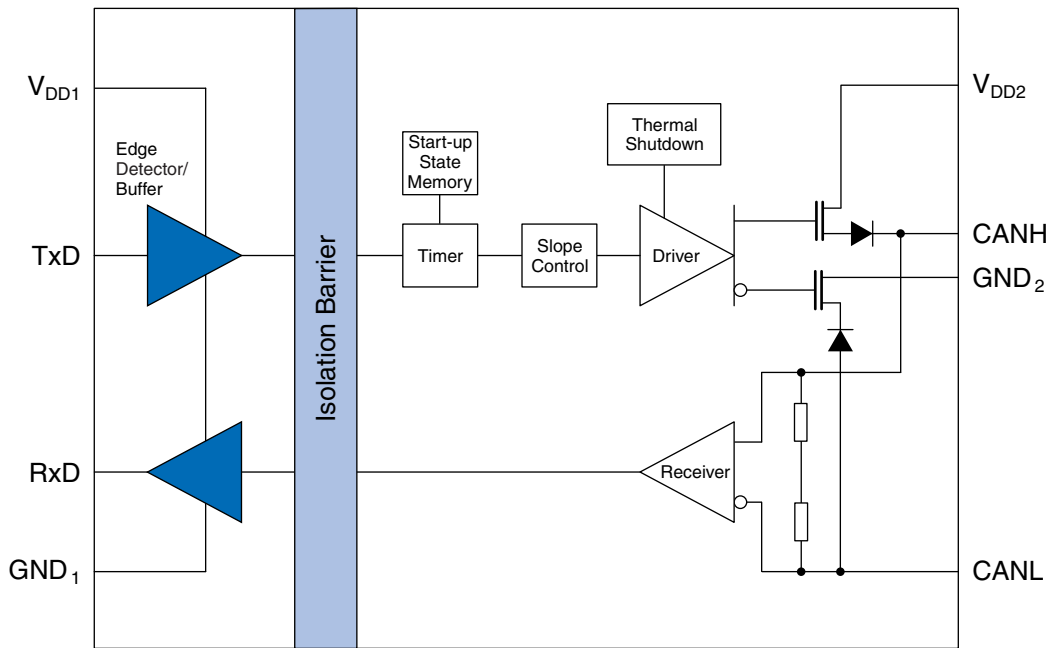
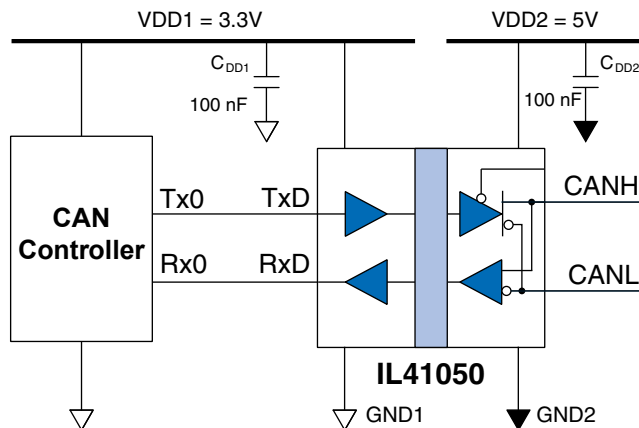


Figure 2. IL41050TT detailed functional diagram.



## Application Information

As Figure 3 shows, the IL41050TT can provide isolation and level shifting between a 5 volt CAN bus and a 3 volt microcontroller:



**Figure 3. Isolated CAN node using the IL41050TT.**

### Power Supply Decoupling

Both  $V_{DD1}$  and  $V_{DD2}$  must be bypassed with 100 nF ceramic capacitors. These supply the dynamic current required for the isolator switching and should be placed as close as possible to  $V_{DD}$  and their respective ground return pins.

### Maintaining Creepage

Creepage distances are often critical in isolated circuits. In addition to meeting JEDEC standards, NVE isolator packages have unique creepage specifications. Standard pad libraries often extend under the package, compromising creepage and clearance. Similarly, ground planes, if used, should be spaced to avoid compromising clearance. Package drawings and recommended pad layouts are included in this datasheet.

### Input Configurations

The TxD input should not be left open as the state will be indeterminate. If connected to an open-drain or open collector output, a pull-up resistor (typically 16 k $\Omega$ ) should be connected from the input to  $V_{DD1}$ .

### Dominant Mode Time-out and Failsafe Receiver Functions

CAN bus latch up is prevented by an integrated Dominant mode timeout function. If the TxD pin is forced permanently low by hardware or software application failure, the time-out returns the RxD output to the high state no more than 765  $\mu$ s after TxD is asserted dominant. The timer is triggered by a negative edge on TxD. If the duration of the low is longer than the internal timer value, the transmitter is disabled, driving the bus to the recessive state. The timer is reset by a positive edge on pin TxD.

If power is lost on Vdd2, the IL41050 asserts the RxD output high when the supply voltage falls below 3.8 V. RxD will return to normal operation when Vdd2 rises above approximately 4.2 V.

### Programmable Power-Up

A unique non-volatile programmable power-up feature prevents unstable nodes. A state that needs to be present at node power up can be programmed at the last power down. For example if a CAN node is required to “pulse” dominant at power up, TxD can be sent low by the controller immediately prior to power down. When power is resumed, the node will immediately go dominant allowing self-check code in the microcontroller to verify node operation. If desired, the node can also power up silently by presetting the TxD line high at power down. At the next power on, the IL41050 will remain silent, awaiting a dominant state from the bus.

The microcontroller can check that the CAN node powered down correctly before applying power at the next “power on” request. If the node powered down as intended, RxD will be set high and stored in the IL41050’s non-volatile memory. The level stored in the RxD bit can be read before isolated node power is enabled, avoiding possible CAN bus disruption due to an unstable node.

## Replacing Non-Isolated CAN Transceivers

The IL41050 is designed to replace common non-isolated CAN transceivers such as the Philips/NXP TJA1050 with minimal circuit changes. Some notable differences:

- Some non-isolated CAN transceivers have internal TxD pull-up resistors, but the IL41050 TxD input should not be left open. If connected to an open-drain or open collector output, a pull-up resistor (typically 16 k $\Omega$ ) should be connected from the input to  $V_{DD1}$ .
- Initialization behavior varies between CAN transceivers. To ensure the desired power-up state, the IL41050 should be initialized with a TxD pulse (low-to-high for recessive initialization), or shut down the transceiver in the desired power-up state (the “programmable power-up feature”).
- Many non-isolated CAN transceivers have a “sleep mode” select input (“S”) or  $V_{REF}$  output. These pins are not available on the IL41050TT. Please select the NVE IL41050TA if these pins are required.

## Replacing Other Isolated CAN Transceivers

The IL41050TT is a pin-for-pin direct replacement for the Texas Instruments ISO1050DW Isolated CAN Transceiver, with advantages of much better reliability and longer barrier life, less EMI emissions, and true 8 mm external creepage per IEC 60601.

## Electrostatic Discharge Sensitivity

This product has been tested for electrostatic sensitivity to the limits stated in the specifications. However, NVE recommends that all integrated circuits be handled with appropriate care to avoid damage. Damage caused by inappropriate handling or storage could range from performance degradation to complete failure.

## Electromagnetic Compatibility

The IL41050 is fully compliant with generic EMC standards EN50081, EN50082-1 and the umbrella line-voltage standard for Information Technology Equipment (ITE) EN61000. The IsoLoop Isolator's Wheatstone bridge configuration and differential magnetic field signaling ensure excellent EMC performance against all relevant standards. NVE conducted compliance tests in the categories below:

### EN50081-1

Residential, Commercial & Light Industrial  
Methods EN55022, EN55014

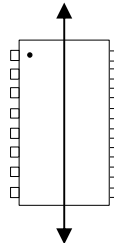
### EN50082-2: Industrial Environment

Methods EN61000-4-2 (ESD), EN61000-4-3 (Electromagnetic Field Immunity), EN61000-4-4 (Electrical Transient Immunity), EN61000-4-6 (RFI Immunity), EN61000-4-8 (Power Frequency Magnetic Field Immunity), EN61000-4-9 (Pulsed Magnetic Field), EN61000-4-10 (Damped Oscillatory Magnetic Field)

### ENV50204

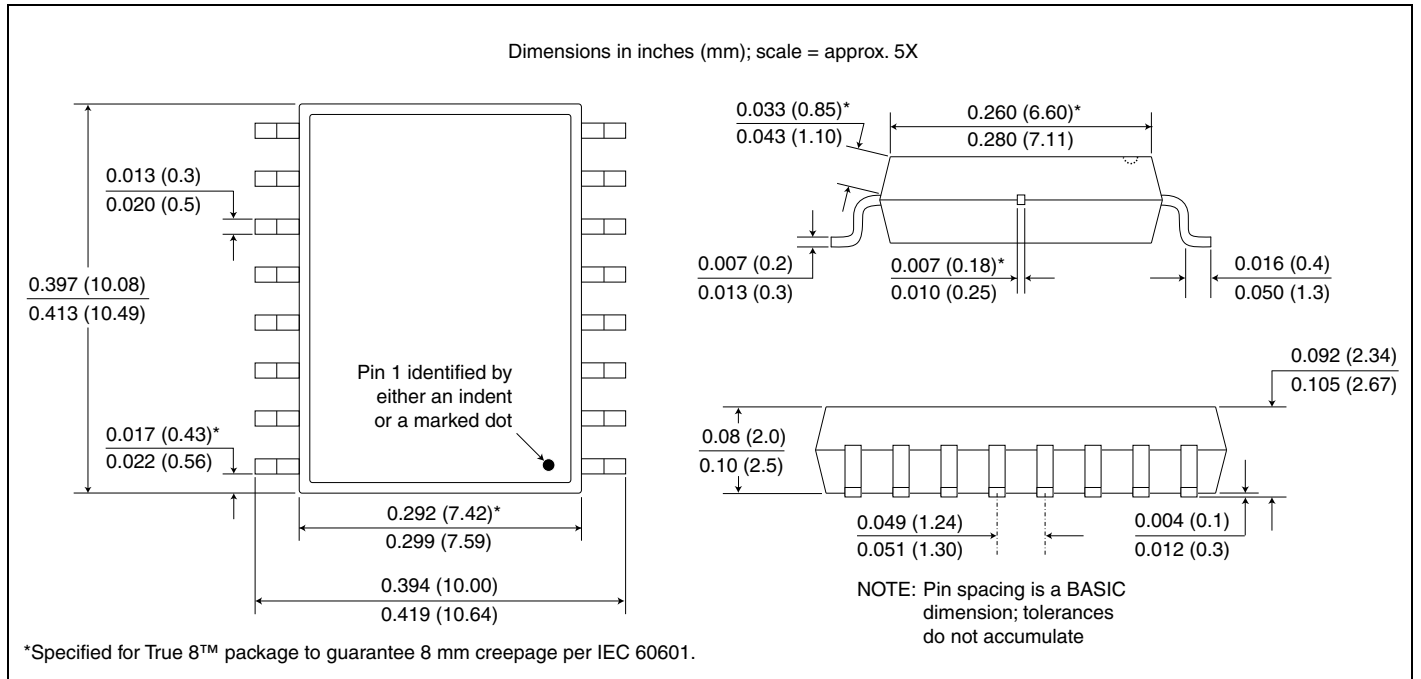
Radiated Field from Digital Telephones (Immunity Test)

Immunity to external magnetic fields is higher if the field direction is "end-to-end" (rather than to "pin-to-pin") as shown in the diagram below:

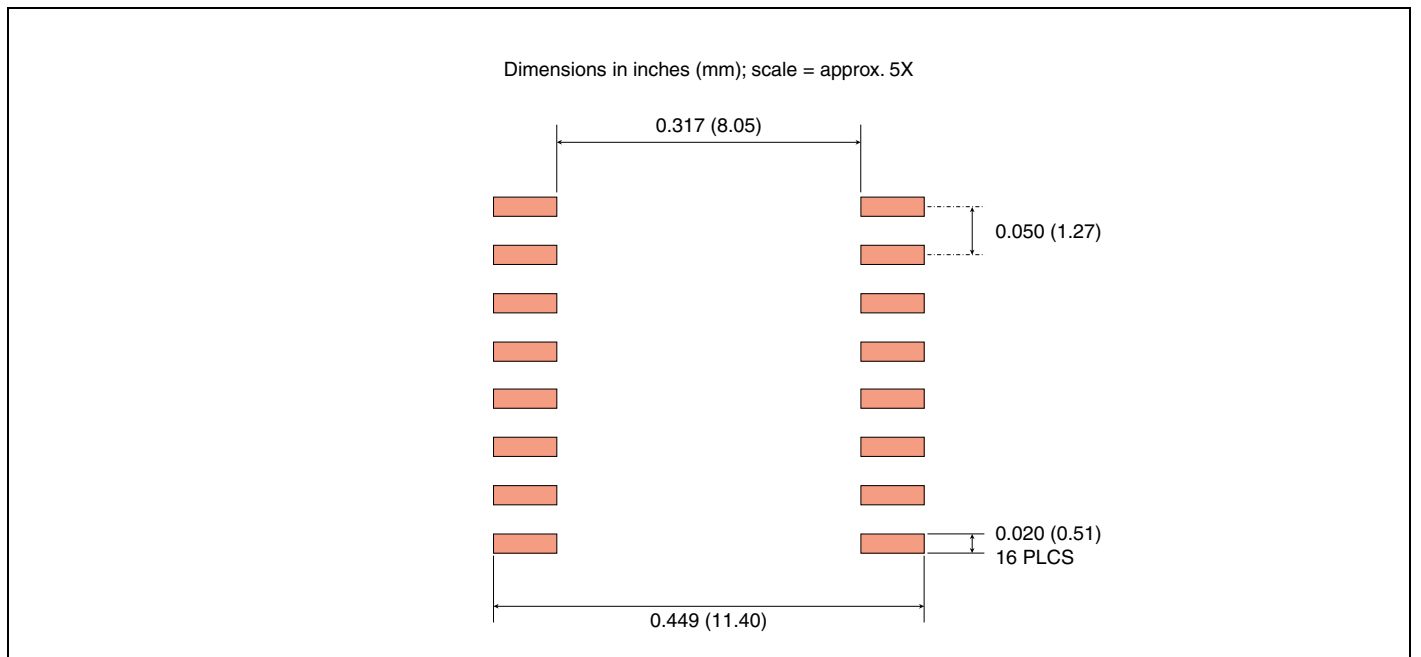


**Figure 4. Orientation for high field immunity.**

## Package Drawing

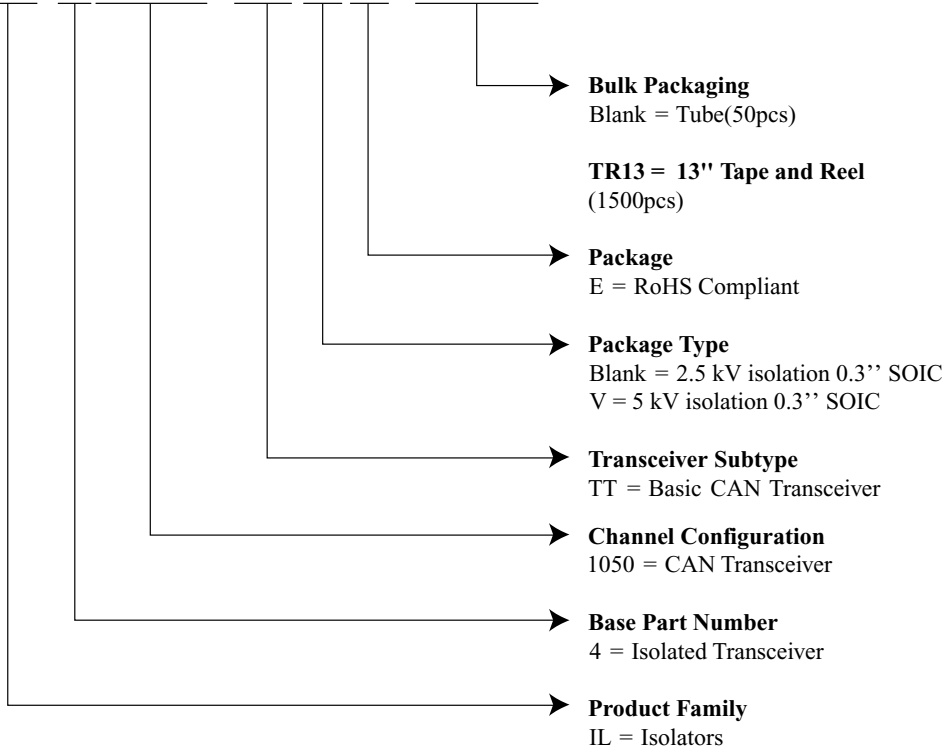


## Recommended Pad Layout



## Ordering Information

IL 41050 TTVE TR13



## Revision History

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**ISB-DS-001-IL41050TT-A**

**Nov. 2015**

**Changes**

- Added 2.5 kV isolation version.
- Initial Release at Rev. A.

**ISB-DS-001-IL41050TT-PRELIM-3**

**Oct. 2015**

**Changes**

- Deleted non-applicable specification sections on p. 5.

**ISB-DS-001-IL41050TT-PRELIM-2**

**Sept. 2015**

**Changes**

- Updated pin descriptions on p. 4.

**ISB-DS-001-IL41050TT-PRELIM**

**Sept. 2015**

Preliminary Release

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